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By: Ruth Montalvo / Ruth Montalvo  
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Date: 03/17/06

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Docket No. JG-SU-5198/500577.20056

Applicant(s): Jun FURUKAWA

Serial No.: 10/784,411

Group: 1722

Filed: February 23, 2004

Examiner: Robert M. Kunemund

For: METHOD OF IDENTIFYING DEFECT DISTRIBUTION IN SILICON SINGLE CRYSTAL  
INGOT

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

**STATUS REQUEST**

Sir,

Please advise the status of the above-identified application and when we can expect to receive an official communication.

Please direct all future telephone calls to:

Jules E. Goldberg, Esq.  
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at  
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Respectfully submitted,

By:

Jules E. Goldberg, Reg. No. 24,408

March 17, 2006  
JEG:ram